

Date: June 2, 2002

Page 1 of 2

FORM PTO-1449 (Colb)	APPlicant DOCKET NO. COLB-203	SERIAL NUMBER 10/069,253
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION STATEMENT	APPLICANT GULETSKY, et al.	EXAMINER (N/A) <i>C. Curtis</i>
	FILING DATE February 20 2002	GROUP ART UNIT (N/A) 2872

U.S. PATENT DOCUMENTS

Examiner's Initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
<i>CXC</i>	AA	5,450,218	Sep. 1995	Heanue, et al.	_____	_____	
<i>CXC</i>	AB	5,932,119	Aug. 1999	Kaplan, et al.	_____	_____	
<i>CXC</i>	AC	5,291,317	Mar. 1994	Newswanger	_____	_____	
<i>CXC</i>	AD	5,592,313	Jan. 1997	Hart	_____	_____	
<i>CXC</i>	AE	5,745,267	Apr. 1998	Hart	_____	_____	
<i>CXC</i>	AF	5,515,183	May 1996	Hashimoto	_____	_____	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRANS- LATION
<i>CXC</i>	AG	RU 2,008,288	_____	_____	_____	_____	_____

OTHER ART (Including Author, Bills, Pertinent Pages, Etc.)

<i>CXC</i>	AH	B.R. Brown, et al., "Complex Spatial Filtering with Binary Masks", Published in Applied Optics, Vol. 5, p. 967ff, 1966.
<i>CXC</i>	AI	W.H. Lee, "Binary Synthetic Holograms", Published in Applied Optics, Vol. 13, p. 1677ff, 1974.
<i>CXC</i>	AJ	W.T. Cathey, "The Effect of Finite Sampling in Holography", in Optik, Vol. 27, p. 317ff, 1968.
<i>CXC</i>	AK	J.P. Allebach, et al., "Aliasing Error in Digital Holography", in Journal of Applied Optics, Vol. 15, p. 2183ff, 1976.
<i>CXC</i>	AL	J.W. Goodman, et al., "Some Effects of Fourier Domain Phase Quantization", in IBM Journal of Research and Development, Vol. 14, p. 478ff, 1970.
EXAMINER:	<i>Braig H. Curtis</i>	DATE CONSIDERED: <i>23 September '03</i>
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		

FORM PTO-1449 (Col. 1)	ATTY DOCKET NO. COLB-203	SERIAL NUMBER 10/069,253
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION STATEMENT	APPLICANT GULETSKY, et al.	EXAMINER (N/A) <i>c-curtis</i>
	FILING DATE February 20, 2002	GROUP ART UNIT (N/A) 2872

U.S. PATENT DOCUMENTS

Examiner's Initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
<i>CHC</i>	AA	5,157,674	Oct. 1992	Lawandy	_____	_____	
<i>CHC</i>	AB	5,253,198	Oct. 1993	Birge, et al.	_____	_____	
<i>CHC</i>	AC	5,289,407	Feb. 1994	Strickler, et al.	_____	_____	
<i>CHC</i>	AD	5,325,324	Jun. 1994	Rentzepis, et al.	_____	_____	
<i>CHC</i>	AE	5,761,111	Jun. 1998	Glezer	_____	_____	
<i>CHC</i>	AF	5,786,560	Jul. 1998	Tatah, et al.	_____	_____	

FOREIGN PATENT DOCUMENTS


		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRANS- LATION
	AG	_____	_____	<i>NONE</i>	_____	_____	_____

OTHER ART (Including Author, Bills, Pertinent Pages, Etc.)

<i>CHC</i>	AH	P.S. Naidu, "Quantization Noise in Binary Holograms", in Optics Communications, Vol. 15, p. 361ff, 1975.
<i>CHC</i>	AI	B.R. Brown, et al., "Computer Generated Binary Holograms", Published in IBM Journal of Research and Development, Vol. 13, p. 168ff, 1969.
<i>CHC</i>	AJ	Yu. N. Denisyuk, "On the Reproduction, of the Optical Properties of an Object as Mirrored in the Wave Field of its Scattered Radiation", Published in Optics and Spectroscopy, Vol. 15, pp. 522-532, 1962.
<i>CHC</i>	AK	D. Brown, et al., "Multi-Element Diffractive Optical Designs Using Evolutionary Programming", Published in SPIE, Vol. 2404, pp. 17-27, 1995.
<i>CHC</i>	AL	Van Heerden, "Note on Optical Information Storage in Solids", Published in Applied Optics, 2, pp. 764ff, 1963.

EXAMINER: *Craig H. Curtis*DATE CONSIDERED: *23 September 2003*

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FORM PTO-1449 (Colb)	ATTY DOCKET NO. COLB 203	SERIAL NUMBER 10/069,253
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION STATEMENT	APPLICANT GULETSKY, et al.	EXAMINER (N/A) <i>e.curtis</i>
	FILING DATE July 23, 2002	GROUP ART UNIT 2872

U.S. PATENT DOCUMENTS

Examiner's Initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
<i>exc</i>	AA	6,087,617	Jul. 2000	Troitski, et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						

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FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRANS- LATION
	AI						
	AJ						
	AK						

OTHER ART (Including Author, Bills, Pertinent Pages, Etc.)

	AL	Patent Abstracts of Japan, Vol. 2000 No. 05, 14 Sept. 2000 & JP 2000 056112.
<i>exc</i>	AM	Kazanskly, N L et al., "Computer-Aided Design of Diffractive Optical Elements", Optical Engineering, Vol. 33, No. 10, October 1994, pp. 3156-3166.
EXAMINER: <i>Craig H. Curtis</i>		DATE CONSIDERED: <i>23 September 2003</i>
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10/069253

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PTO/SB/08A (08-00)

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U. S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Complete if Known	
				Application Number	
				Filing Date	Herewith
				First Named Inventor	Guletsky, et al.
				Group Art Unit	
				Examiner Name	Not Yet Assigned <i>E. Curtis</i>
Sheet	1	of	1	Attorney Docket Number	NY-COLB 202-US

U.S. PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
<i>CHC</i>	A	5,450,218		Heanue, et al.	9/12/95	
	B	/	/	/	/	/
	C	/	/	/	/	/
	D	/	/	/	/	/
	E	/	/	/	/	/

FOREIGN PATENT DOCUMENTS								
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Office ³	Number ⁴	Kind Code ⁵ (if known)				
					<i>NONE</i>			

Examiner Signature	<i>Craig H. Curtis</i>	Date Considered	<i>22 Sept. '03</i>
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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the application number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.